

<b>Notice of References Cited</b>	Application/Control No. 10/538,505	Applicant(s)/Patent Under Reexamination MURAKAMI, KEIICHI	
	Examiner THIEM PHAN	Art Unit 3729	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**FOREIGN PATENT DOCUMENTS**

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